

**Search Notes**

Application/Control No.

09/664,855

Examiner

Huy D. Nguyen

Applicant(s)/Patent under  
Reexamination

ENOKI ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
455	574	2/12/2003	HN
	572		
	127.5		
	343.1		
	435.1		
	343.2		
	343.5		
Updated	search	9/22/2005	HN
Updated	search	9/21/2006	HN
Updated	search	7/22/2007	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
455	574	7/22/2007	HN
	572		
	343.1		

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	9/22/2005	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	9/21/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	7/22/2007	HN
See interference search printout.	7/22/2007	HN